CLAIMS

1. An inspection method for inspecting a geometric pattern of an information recording section consisting of a ferromagnetic thin-film layer formed on a master disk from which initial information is copied to a magnetic recording medium, said method comprising:

(a) forming alignment marks in a plurality of positions on a circumference concentric with the recording section simultaneously with forming the information recording section on said master disk;

(b) providing non-defective product information representing a non-defective geometric pattern of the information recording section;

(c) capturing the image of the information recording section of said master disk and the image of said marks; and

(d) aligning the image of the information recording section with the non-defective product information with respect to the image of said marks, then comparing the image of the information recording section with the non-defective product information to inspect the geometric pattern of the information recording section.

2. The inspection method according to claim 1, wherein said step (b) provides as said non-defective product information the image of the information recording section of a master disk that is judged as being non-defective among master disks manufactured.

3. The inspection method according to claim 1, wherein said step (b) generates the non-defective product information from design data about the information recording section.

4. The inspection method according to claim 3, wherein said step (b) generates the non-defective product information by making a correction to the design data about the information recording section, said correction being entailed by a difference between the design data and the geometry of a product.

5. The inspection method according to claim 4, wherein said step (b) generates the non-defective product information by making a correction of adding a dead zone to an outline of the information recording section among said design data about the information recording section.

6. The inspection method according to claim 4 or 5, wherein after aligning the image of the information recording section with the non-defective information with respect to the image of said marks, said step (d) repeats:

(d-1) dividing the image of the information recording section to obtain a division image;

(d-2) generating the non-defective information of a corresponding part each time said division image is obtained; and

(d-3) comparing said division image with the non-defective information of the corresponding part to inspect the geometric pattern of the division image of the information recording section.

7. An inspection method for inspecting a mask pattern used in forming an information recording section consisting of a ferromagnetic thin-film layer on a master disk from which initial information is copied to a magnetic recording medium, said method comprising:

(a) forming alignment marks in a plurality of positions on a circumference concentric with the information recording section simultaneously with forming a geometric pattern serving as an information recording section in said mask pattern;

(b) providing non-defective product information representing a geometric pattern of a non-defective product geometric pattern of the information recording section;

(c) capturing an image of the information recording section of said mask pattern and an image of said marks; and

(d) aligning the image of the information recording section with the non-defective product information with respect to the image of said marks, then comparing the image of the information recording section with the non-defective product information to inspect the geometric pattern of the information recording section.